



JINSP Company Ltd.
spectralanalyser.com

92% High Quantum Spectrometer for Film Thickness Measurement

Our Product Introduction

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Basic Information

- Place of Origin: CHINA
- Brand Name: JINSP
- Certification: ISO9001
- Model Number: SR100Q
- Minimum Order Quantity: 1
- Price: Negotiable
- Packaging Details: International Shipping Package
- Delivery Time: 90-120 working days
- Payment Terms: T/T, Western Union
- Supply Ability: 100PCS/90-120 days



Product Specification

- Spectral Range: 200nm - 1100nm
- Effective Pixels: 1024*122
- Quantum Efficiency: QE92%peak@650nm, 83%@232nm
- SNR: 1000:1



More Images



Product Description

92% High Quantum Spectrometer for Film Thickness Measurement

Thin film technology plays a vital role across industries like semiconductors, solar energy, displays, and optical coatings. Precise thickness measurement is crucial for analyzing surface morphology. Photoelectric methods, with their non-contact, nondestructive, and efficient advantages, will keep advancing film measurement. Combining smart algorithms with optical devices enables accurate thickness and quality assessment, driving process improvements and industrial innovation.

Product Parameters:

Detector	Chip Type	Back-illuminated TE-cooled Hamamatsu S7031
	Effective Pixel	1024*122
	Pixel Size	24*24μm
	Sensing Area	24.576*2.928mm
Optical Parameters	Optical Design	F/4 cross-type
	Numerical Aperture	0.13
	Focal Length	100mm
	Entrance Slit Width	10μm,25μm,50μm,100μm,200μm (customizable)
	Fiber Interface	SMA905,free space
Electrical Parameters	Integration Time	8ms-3600s
	Data Output Interface	USB3.0,RS232,RS485,20pin connector
	ADC Bit Depth	16-bit
	Power Supply	5V
	Operating Current	<3.5A
Physical Parameters	Operating Temperature	10 ~40
	Storage Temperature	-20 ~60
	Operating Humidity	<90%RH (no condensation)
	Dimensions	180mm*120mm*50mm
	Weight	1.2kg

List of Product Models:

Model	Spectral Range(nm)	Resolution(nm)	Slit(μm)
SR100Q-G21	200~950	6.8	200
		2.2	50
SR100Q-G22	350~1100	1.5	25
		1.0	10
SR100Q-G23	200~775	1.6	50
		1.0	25
SR100Q-G24	350~925	0.7	10
SR100Q-G25	532~690(4400cm-1)*	13cm-1	50
SR100Q-G26	638~800(3200cm-1)*	10cm-1	25
SR100Q-G27	785~1050(3200cm-1)*	11cm-1	50

Note: The*are primarily designed for Raman applications, with the corresponding Raman.

Technical Characteristics:

High quantum efficiency, 92%peak@650nm, 83%@232nm

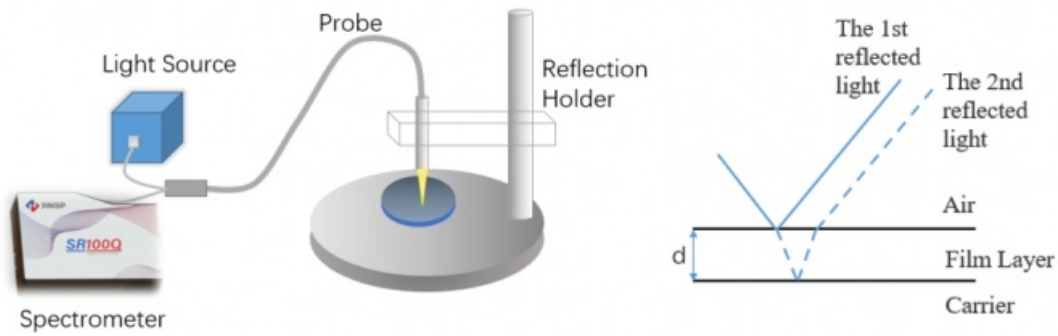
High SNR: Ultra-low dark noise under long integration time, SNR is as high as 1000:1

Noise-free clear processing of weak signal in long exposure, strong adaption to environment

Low-noise and high-speed circuit: USB3.0

Measurement Method:

The light from the source is guided through an optical fiber probe onto the film surface. Upon entering the film (a denser medium), partial reflection occurs at the air-film interface (first reflected beam), while the transmitted light reflects again at the film-substrate boundary (second reflected beam). Both beams travel back through the receiving fiber to a spectrometer, creating an interference pattern due to their optical path difference. Film thickness (d) is derived using the extremum method, accounting for incident angle (θ), refractive index (n), and spectral peak/trough positions. Thicker films yield denser fringes, whereas longer wavelengths produce sparser patterns. Optimal wavelength range and resolution must be selected for accurate measurement.



Typical Applications:

Detect absorption, transmittance and reflection Spectrum

Light source and laser wavelength characterization

OEM product module: Fluorescence spectrum, Raman spectrum, etc.

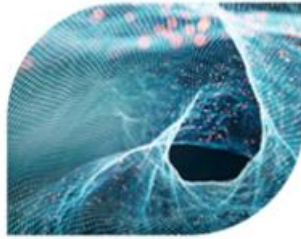
Ultra High Sensitivity Fiber Optic Spectrometer

Research-grade CCD chip S7031

SR100Q



Technical Characteristics



High quantum efficiency,
92%peak@650nm,
83%@232nm



High SNR: Ultra-low dark noise
under long integration time,
SNR is as high as 1000:1



Noise-free clear
processing of weak signal
in long exposure, strong
adaption to environment



Low-noise and high-speed
circuit: USB3.0

Typical Applications

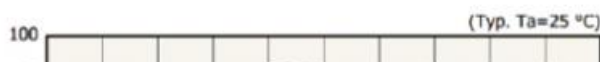
Detect absorption, transmittance and
reflection Spectrum

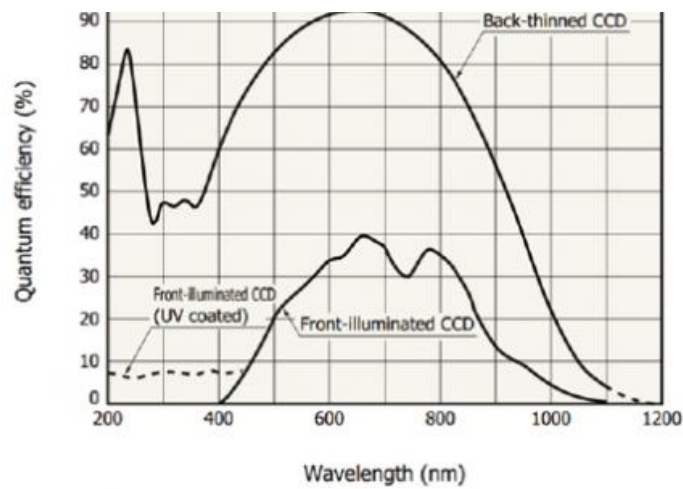


Light source and laser wavelength
characterization

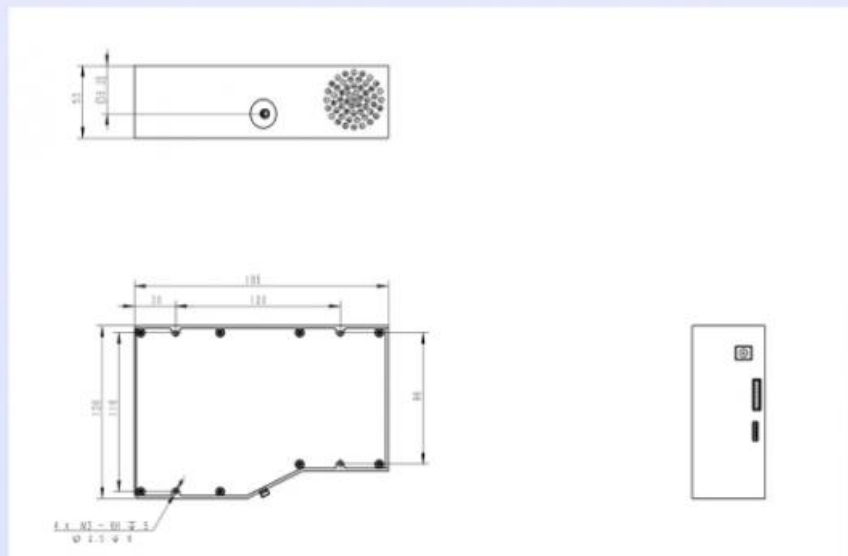


OEM product module: Fluorescence
spectrum, Raman spectrum, etc.





CCD Quantum Efficiency Curve



Installation dimension drawing

Company Introduction:

JINSP Company Limited, abbreviated as "JINSP", is a professional supplier with over 17 years of experience in spectral detection technology products, including Raman, FT-IR, LIBS technologies, etc. After 17 years of technology accumulation, the company's core key technologies have reached the international leading position at the level, and the cumulative number of patent applications exceeded 200.

In addition to its main headquarters located in the bustling city of Beijing, JINSP has established a fully owned subsidiary manufacturing facility situated in the province of Jiangsu, China.

JINSP Company received ISO9001:2015, ISO14001:2015, and ISO45001:2018 certifications. JINSP can provide required certifications, such as certification by the Ministry of Public Security or National Institute of Metrology, Environmental Level Certification, IP Level Certification, CE Certification, Transport Identification Report, EU ECAC certification, German ICT Security Testing, etc.

Company Profile



Exhibition



Certifications



FAQ

Q1: This is the first time I use, is it easy to operate?

A1: We will send you manual and guide video in English, it can teach you how to operate the spectrometer. Also our technicians will offer professional technical operation meetings.

Q2: Can you offer a operation training?

A2: Your technicians can come to our factory for a training. Jinsp engineers can go to your place for local support (installation, training, debugging, maintenance).

Q3: What's your website?

A3: You can visit: www.jinsptech.com

Q4: What about your quality assurance?

A4: We have a quality inspection team. All goods will go through quality inspection before shipment. We can send you pictures for inspection.



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